U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,930,783	07-1999	Li et al.	382/230
	B	US-5,579,444	11-1996	Dalziel et al.	382/153
	C	US-6,360,234	03-2002	Jain et al.	707/500.1
	D	US-6,144,375	11-2000	Jain et al.	345/420
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Modestino et al, A Markov Random Field Model-Based Approach to Image Interpretation, June 1992, IEEE Transactions on Pattern Ananlysis and Machine Intelligence, ISBN: 0162-8828, Vol. 14, No. 6, Pages 606-615.
	V	Kim et al, Efficient Image Understanding Based on the Markov Random Field Model and Error Backpropagation Network, 1992, IEEE Transaction on Pattern Analysis and Machine Intelligence, ISBN: 0-8186-2910-X, Pages 441-444.
	W	Kim et al, An Integration Scheme for Image Segmentation and Labeling Based on Markov Random Field Model, January 1996, IEEE Transaction on Pattern Analysis and Machine Intelligence, ISBN: 0162-8828, Vol. 18, No.1, Pages 69-73.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.